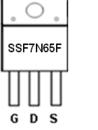
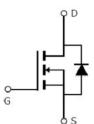


Main Product Characteristics:

V _{DSS}	650V
R _{DS} (on)	1.26Ω (typ.)
I _D	7A







TO220F

Marking and pin Assignment

Schematic diagram

Features and Benefits:

- Advanced Process Technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature



Description:

These N-Channel enhancement mode power field effect transistors are produced using silikron proprietary MOSFET technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switch mode power supplies.

Absolute max Rating:

Symbol	Parameter	Max.	Units
I _D @ TC = 25°C	Continuous Drain Current, V _{GS} @ 10V	7 ①	
I _D @ TC = 100°C	Continuous Drain Current, V _{GS} @ 10V	4.4 ①	А
I _{DM}	Pulsed Drain Current ②	28	
P _D @TC = 25°C	Power Dissipation ③	52	W
PD @ 10 = 25 C	Linear Derating Factor	0.42	W/°C
V _{DS}	Drain-Source Voltage	650	V
V _{GS}	Gate-to-Source Voltage	± 30	V
E _{AS}	Single Pulse Avalanche Energy @ L=10mH	353	mJ
I _{AS}	Avalanche Current @ L=10mH	8.4	Α
T _J T _{STG}	Operating Junction and Storage Temperature Range	-55 to +150	°C



Thermal Resistance

Symbol	Characterizes	Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-case ③	_	2.4	℃W
В	Junction-to-ambient (t \leq 10s) \oplus	_	62	°C/W
$R_{\theta JA}$	Junction-to-Ambient (PCB mounted, steady-state) ④	_	40	°C ™

Electrical Characterizes $@T_A=25^{\circ}C$ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source breakdown voltage	650	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$
D	R _{DS(op)} Static Drain-to-Source on-resistance		1.26	1.4	Ω	V _{GS} =10V,I _D =3.5A
$R_{DS(on)}$	Static Dialif-to-Source off-resistance	_	2.85	_	12	T _J = 125℃
V	Gate threshold voltage	2	_	4	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
$V_{GS(th)}$	Gate threshold voltage	_	2.0	_	V	T _J = 125℃
1	Drain to Source leakage current	_	_	1		$V_{DS} = 650 V, V_{GS} = 0 V$
I _{DSS}	Drain-to-Source leakage current	_	_	50	μA	T _J = 125℃
1	Cata to Source forward lookage	_	_	100	nA	V _{GS} =30V
I _{GSS}	Gate-to-Source forward leakage	_	_	-100	nA	V _{GS} = -30V
Qg	Total gate charge	_	31.3	_	nC	$I_D = 7A$,
Q_{gs}	Gate-to-Source charge	_	6.4	_		V _{DS} =300V,
Q_{gd}	Gate-to-Drain("Miller") charge	_	11.3	_		V _{GS} = 10V
t _{d(on)}	Turn-on delay time	_	15.7	_		\/ 10\/ \/ 200\/
t _r	Rise time	_	25.6	_	nS	V_{GS} =10V, V_{DS} =300V, R_L =43 Ω , R_{GEN} =25 Ω
t _{d(off)}	Turn-Off delay time	_	92.9	_		I _D =7A
tf	Fall time	_	39.2	_		ID = IA
C _{iss}	Input capacitance	_	1232	_		V _{GS} = 0V
C _{oss}	Output capacitance	_	102	_	pF	V _{DS} = 25V
C _{rss}	Reverse transfer capacitance	_	7.0	_		f = 1MHz

Source-Drain Ratings and Characteristics

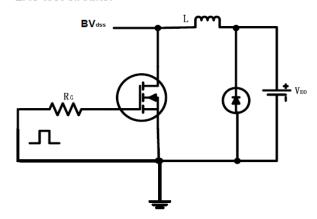
Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
1	Continuous Source Current			7	۸	MOSFET symbol
I _S	(Body Diode)	_	_	,	A	showing the
I _{SM}	Pulsed Source Current			28	А	integral reverse
	(Body Diode)	_	_			p-n junction diode.
V _{SD}	Diode Forward Voltage	_	0.86	1.4	V	I _S =7A, V _{GS} =0V
t _{rr}	Reverse Recovery Time	_	665	_	nS	$T_J = 25^{\circ}\text{C}, I_F = 7\text{A},$
Q _{rr}	Reverse Recovery Charge	_	4096	_	nC	di/dt = 100A/µs

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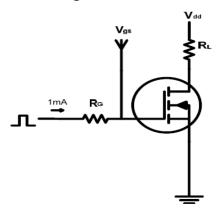


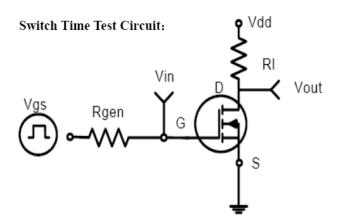
Test circuits and Waveforms

EAS test circuits:

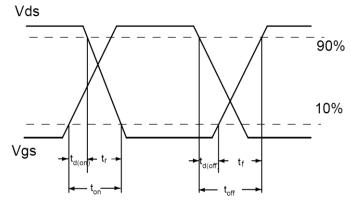


Gate charge test circuit:







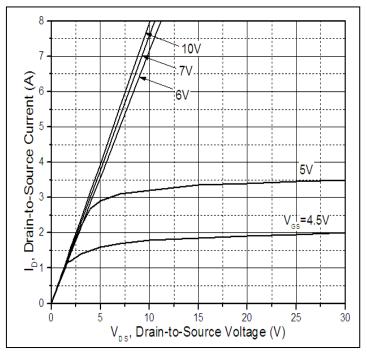


Notes:

- ①Calculated continuous current based on maximum allowable junction temperature.
- ②Repetitive rating; pulse width limited by max junction temperature.
- ③The power dissipation PD is based on max junction temperature, using junction-to-case thermal resistance.
- 4The value of $R_{\texttt{6JA}}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with TA =25°C



Typical electrical and thermal characteristics



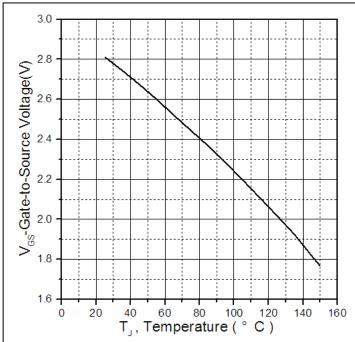


Figure 1: Typical Output Characteristics

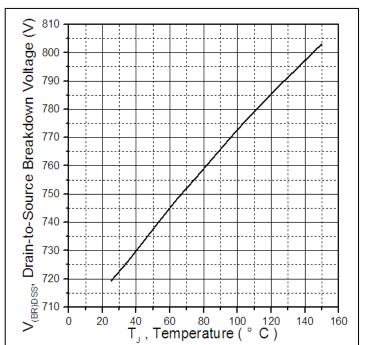


Figure 3. Drain-to-Source Breakdown Voltage Vs.

Case Temperature

Figure 2. Gate to source cut-off voltage

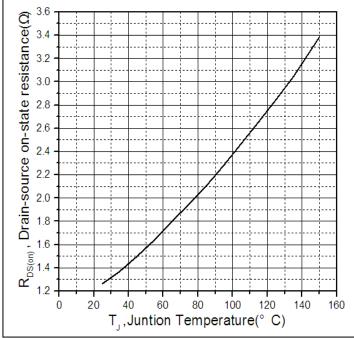
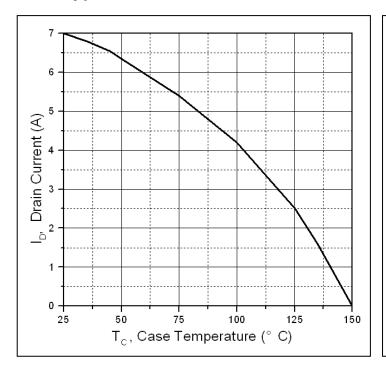


Figure 4: Normalized On-Resistance Vs. Case Temperature



Typical electrical and thermal characteristics



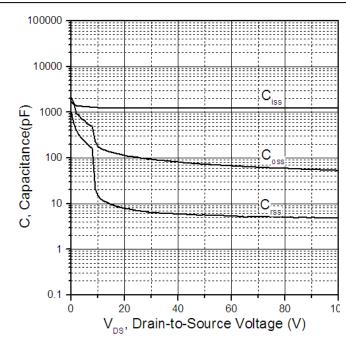


Figure 5. Maximum Drain Current Vs. Case Temperature

Figure 6.Typical Capacitance Vs. Drain-to-Source Voltage

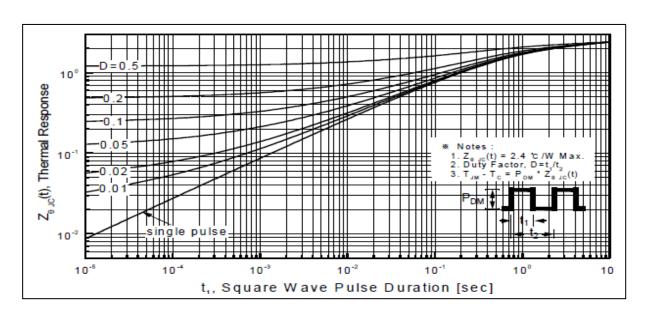
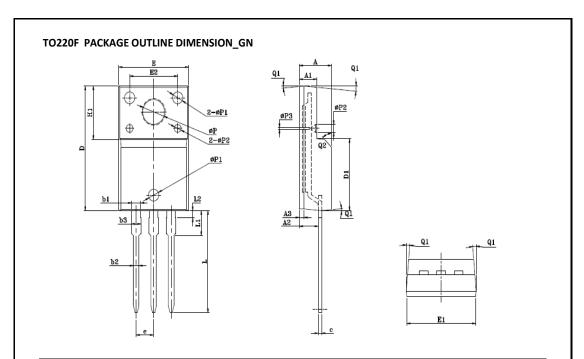


Figure 7. Maximum Effective Transient Thermal Impedance, Junction-to-Case



Mechanical Data:



Cumbal	Dimension In Millimeters			Dimension In Inches			
Symbol	Min	Nom	Max	Min	Nom	Max	
Е	9.960	10.160	10.360	0.392	0.400	0.408	
E1	9.840	10.040	10.240	0.387	0.395	0.403	
E2	6.800	7.000	7.200	0.268	0.276	0.283	
Α	4.600	4.700	4.800	0.181	0.185	0.189	
A1	2.440	2.540	2.640	0.096	0.100	0.104	
A2	2.660	2.760	2.860	0.105	0.109	0.113	
A3	0.600	0.700	0.800	0.024	0.028	0.031	
С	-	0.500	-	-	0.020	-	
D	15.780	15.870	15.980	0.621	0.625	0.629	
D1	8.970	9.170	9.370	0.353	0.361	0.369	
H1	6.500	6.700	6.800	0.256	0.264	0.268	
е		2.54BSC	•		0.10BSC	•	
ФР	3.080	3.180	3.280	0.121	0.125	0.129	
ФР1	1.400	1.500	1.600	0.055	0.059	0.063	
ФР2	0.900	1.000	1.100	0.035	0.039	0.043	
ФР3	0.100	0.200	0.300	0.004	0.008	0.012	
L	12.780	12.980	13.180	0.503	0.511	0.519	
L1	2.970	3.170	3.370	0.117	0.125	0.133	
L2	0.830	0.930	1.030	0.033	0.037	0.041	
Q1	3°	5°	7°	3°	5°	7°	
Q2	43°	45°	47°	43°	45°	47°	
b1	1.180	1.280	1.380	0.046	0.050	0.054	
b2	0.760	0.800	0.840	0.030	0.031	0.033	
b3	-	-	1.420	-	-	0.056	





Ordering and Marking Information

Device Marking: SSF7N65F

Package (Available)
TO220F
Operating Temperature Range
C: -55 to 150 °C

Devices per Unit

Package	Units/	Tubes/Inner	Units/Inner	Inner	Units/Carton
Туре	Tube	Box	Box	Boxes/Carton	Box
				Box	

Reliability Test Program

Test Item	Conditions	Duration	Sample Size
High	T _j =125℃ to 150℃ @	168 hours	3 lots x 77 devices
Temperature	80% of Max	500 hours	
Reverse	V _{DSS} /V _{CES} /VR	1000 hours	
Bias(HTRB)			
High	T _j =150℃ @ 100% of	168 hours	3 lots x 77 devices
Temperature	Max V _{GSS}	500 hours	
Gate		1000 hours	
Bias(HTGB)			

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